



J O U R N A M E N T

ACADEMIC JOURNAL INDEXING & IMPACT ANALYSIS



Certificate of Indexing

This is to certify that the academic journal

2017 IEEE International Electron Devices Meeting (IEDM)

has been formally reviewed and admitted to the Journament Index of Academic Journals, having satisfied the standards required for scholarly indexing, and is hereby awarded a verified Journament Impact Score.



Journament Editorial Board

AUTHORIZED SIGNATORY

REGISTRY № JML-31341

Verify at journament.com/verify/31341

13 August 2021

DATE OF INDEXING